

**SCANNING PROBE MICROSCOPE ASSEMBLY AND METHOD FOR
MAKING SPECTROPHOTOMETRIC, NEAR-FIELD, AND SCANNING
PROBE MEASUREMENTS**

ABSTRACT OF THE DISCLOSURE

A scanning probe microscope assembly that has an atomic force measurement (AFM) mode, a scanning tunneling measurement (STM) mode, a near-field spectrophotometry mode, a near-field optical mode, and a hardness testing mode for examining an object.

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